

### **FDS6670S**

## 30V N-Channel PowerTrench<sup>o</sup> SyncFET<sup>™</sup>

### **General Description**

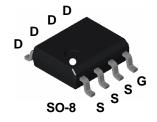
The FDS6670S is designed to replace a single SO-8 MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low  $R_{\text{DS(ON)}}$  and low gate charge. The FDS6670S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology.

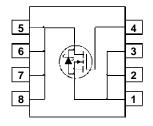
### **Applications**

- DC/DC converter
- Motor drives

### **Features**

- 13.5 A, 30 V.  $R_{DS(ON)} = 9 \text{ m}\Omega$  @  $V_{GS} = 10 \text{ V}$   $R_{DS(ON)} = 12.5 \text{ m}\Omega$  @  $V_{GS} = 4.5 \text{ V}$
- Includes SyncFET Schottky body diode
- Low gate charge (24nC typical)
- High performance trench technology for extremely low R<sub>DS(ON)</sub> and fast switching
- High power and current handling capability





### Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		30	V
$V_{GSS}$	Gate-Source Voltage		±20	V
I <sub>D</sub>	Drain Current - Continuous	(Note 1a)	13.5	А
	- Pulsed		50	
$P_D$	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1	
$T_J$ , $T_{STG}$	Operating and Storage Junction Temperature Range		-55 to +150	°C

### **Thermal Characteristics**

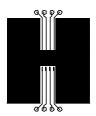
R <sub>θJA</sub>	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

### **Package Marking and Ordering Information**

Device Marking	Device	Reel Size	Tape width	Quantity
FDS6670S FDS6670S		13"	13" 12mm	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics	1	· I	I	I	I
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	30			V
ΔBV <sub>DSS</sub> ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C		24		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			500	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V},  V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)	•				
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 1 \text{ mA}$	1	2.2	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 1 mA, Referenced to 25°C		-6.2		mV/°C
R <sub>DS(on)</sub>	Static Drain–Source On–Resistance	$V_{GS} = 10 \text{ V}, \qquad I_D = 13.5 \text{ A}$ $V_{GS} = 4.5 \text{ V}, \qquad I_D = 11.2 \text{ A}$ $V_{GS} = 10 \text{ V}, I_D = 13.5 \text{ A}, T_J = 100^{\circ}\text{C}$		7 9.5 9	9 12.5 12.5	mΩ
I <sub>D(on)</sub>	On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	50			Α
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 13.5 \text{ A}$		45		S
Dynamic	Characteristics			•	•	•
C <sub>iss</sub>	Input Capacitance	$V_{DS} = 15 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		2674		pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		751		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			254		pF
Switchin	ng Characteristics (Note 2)	•				
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 1 \text{ A}, \\ V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		11	20	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		10	20	ns
t <sub>d</sub> ( <sub>off</sub> )	Turn-Off Delay Time			44	70	ns
t <sub>f</sub>	Turn-Off Fall Time			23	37	ns
Q <sub>q</sub>	Total Gate Charge	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 13.5 \text{ A},$		24	34	nC
$Q_{gs}$	Gate-Source Charge	$V_{GS} = 5 V$		7.3		nC
$Q_{gd}$	Gate-Drain Charge			6		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings		•	•	
Is	Maximum Continuous Drain-Source	Diode Forward Current			3.5	Α
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V},  I_S = 3.5 \text{ A}  \text{(Note 2)}$ $V_{GS} = 0 \text{ V},  I_S = 7 \text{ A}  \text{(Note 2)}$		0.4 0.5	0.7	V
t <sub>rr</sub>	Diode Reverse Recovery Time	I <sub>F</sub> = 13.5A,		26.8		nS
Q <sub>rr</sub>	Diode Reverse Recovery Charge	$d_{iF}/d_t = 300 \text{ A/}\mu\text{s}$ (Note 3)		47.2		nC

1. R<sub>8JA</sub> is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $\rm R_{\theta JC}$  is guaranteed by design while  $\rm R_{\theta CA}$  is determined by the user's board design.



a) 50°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper



b) 105°C/W when mounted on a .04 in² pad of 2 oz copper



c) 125°C/W when mounted on a minimum pad.



- 2. Pulse Test: Pulse Width < 300µs, Duty Cycle < 2.0%
- 3. See "SyncFET Schottky body diode characteristics" below.

### **Typical Characteristics**

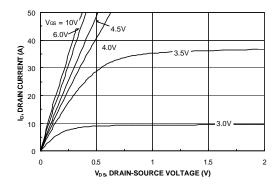


Figure 1. On-Region Characteristics.

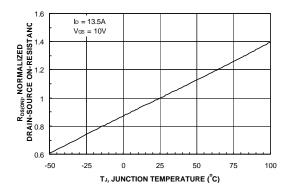


Figure 3. On-Resistance Variation with Temperature.

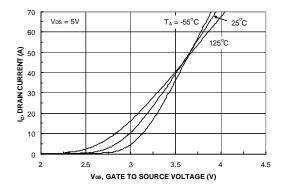


Figure 5. Transfer Characteristics.

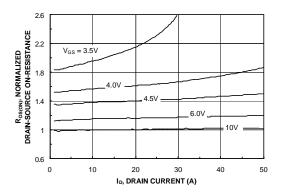


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

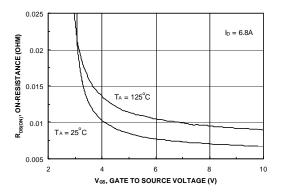


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

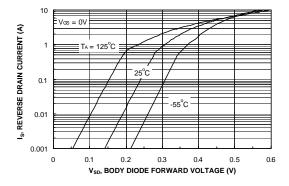
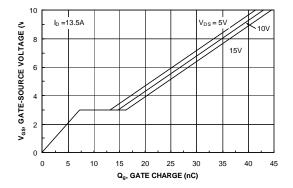


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

### Typical Characteristics (continued)



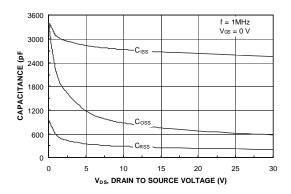
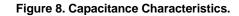
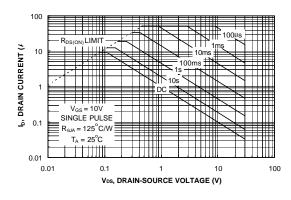


Figure 7. Gate Charge Characteristics.





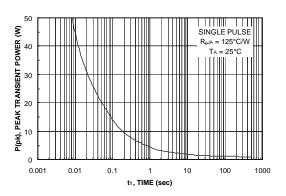


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

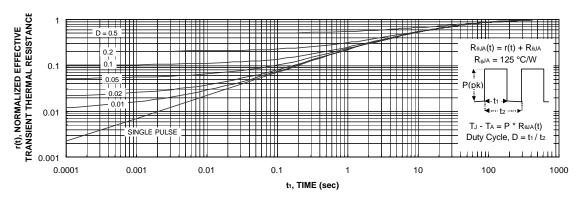


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

### Typical Characteristics (continued)

# SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDS6670S.

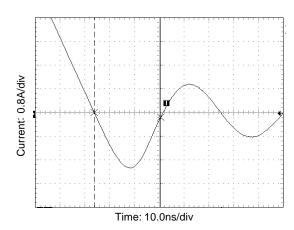


Figure 12. FDS6670S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDS6670A).

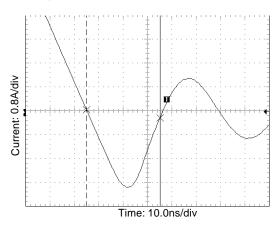


Figure 13. Non-SyncFET (FDS6670A) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

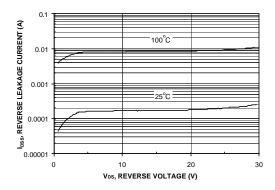


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.

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